

Circuits Lab 6

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Experiment 1

In this experiment, we wanted to evaluate how well-matched four nMOS transistors on the same die are.

Experiment 2

In this experiment, we explore how series and parallel combinations of n MOS transistors behave, and what affect these combinations have on the channel current, I_{sat} , as a function of gate voltage, V_G . In order to accomplish this comparison, we collected data for the channel current in both ohmic and saturation regions of operation for a single n MOS transistor, two transistors in parallel, and two transistors in series.